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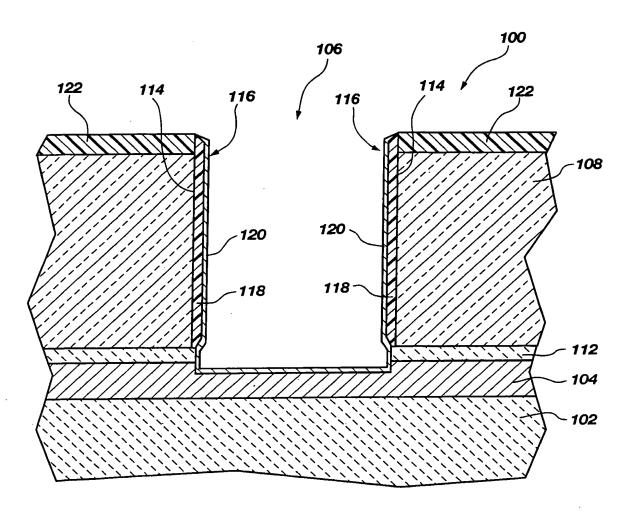


Fig. 1



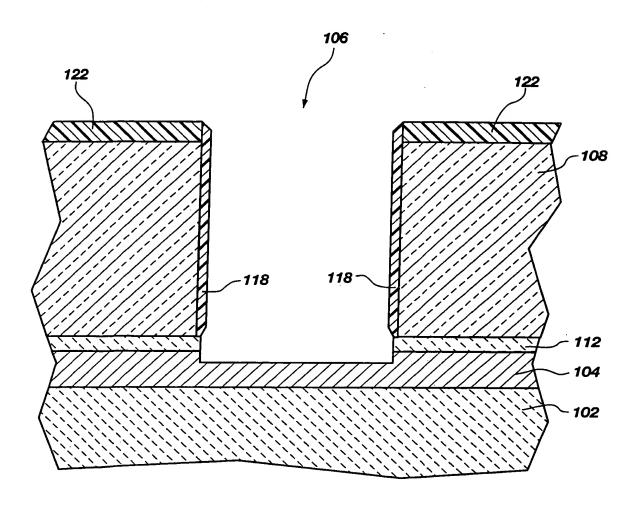


Fig. 2





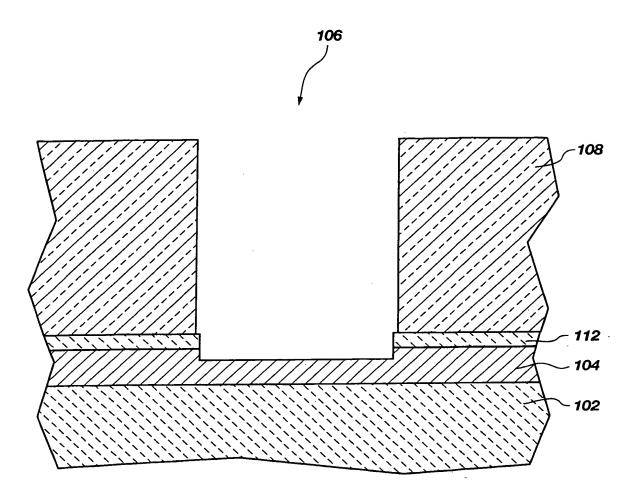


Fig. 3

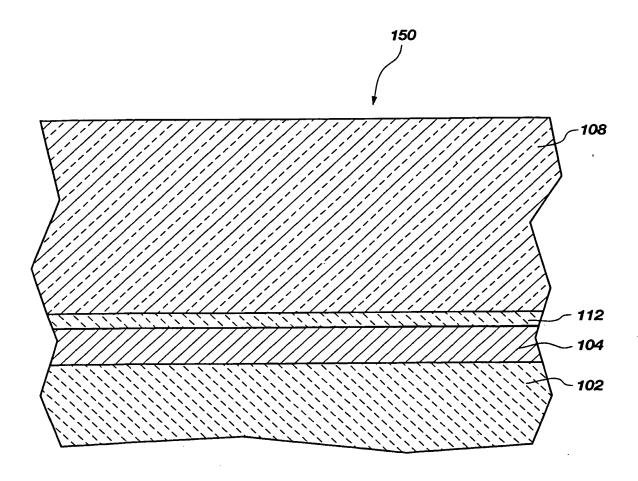


Fig. 4

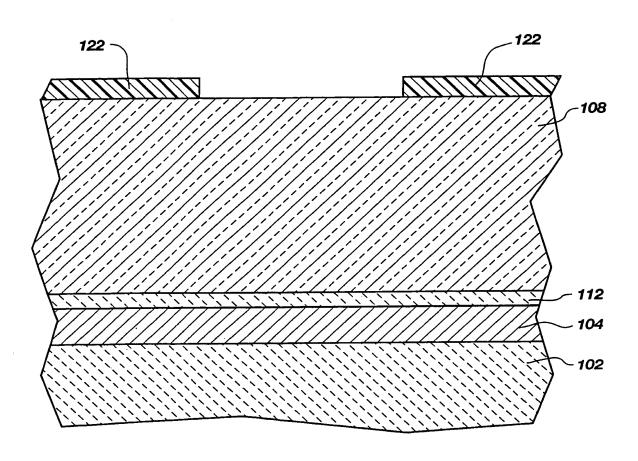


Fig. 5

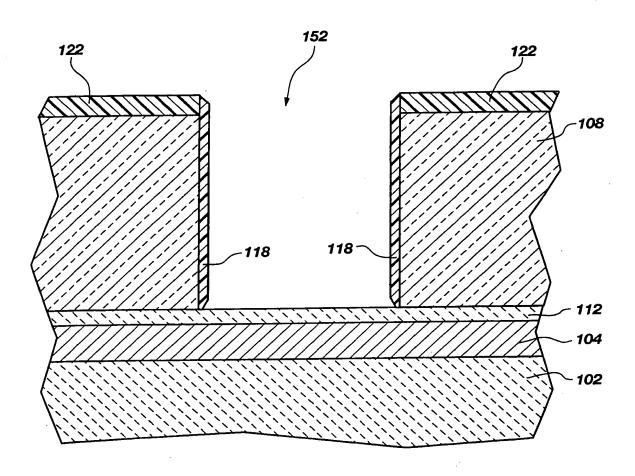


Fig. 6



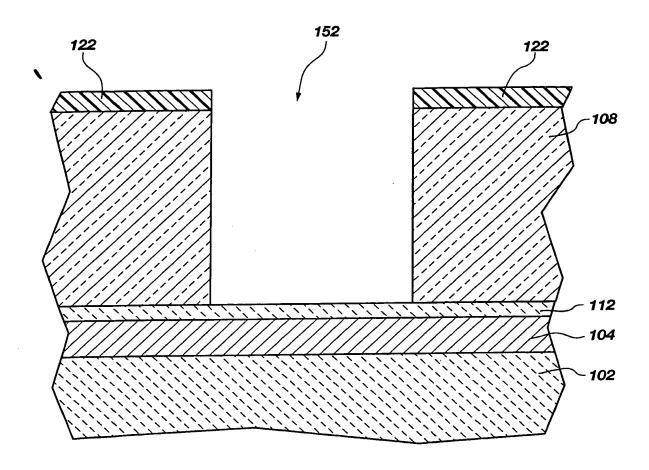


Fig. 7

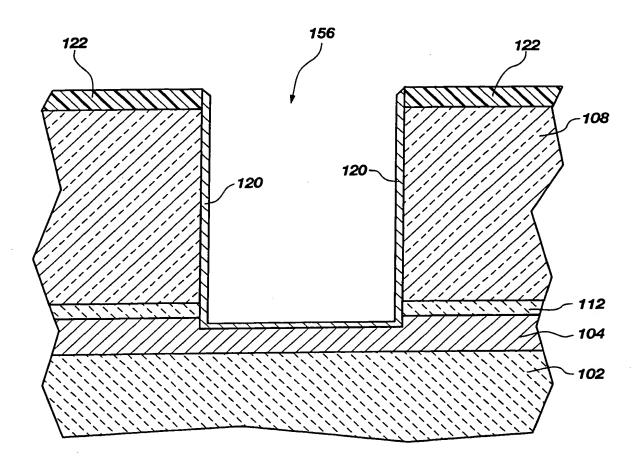


Fig. 8

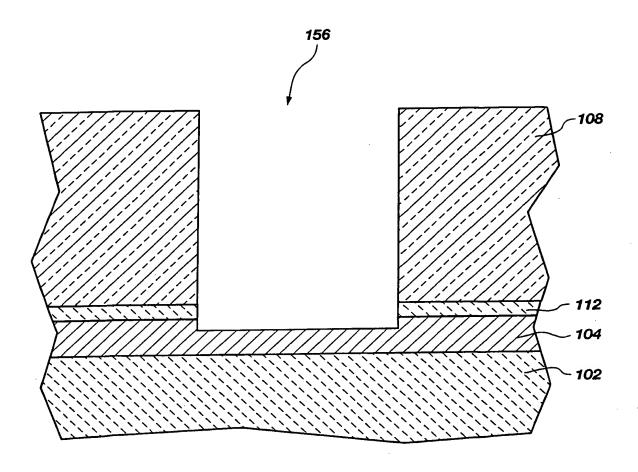


Fig. 9



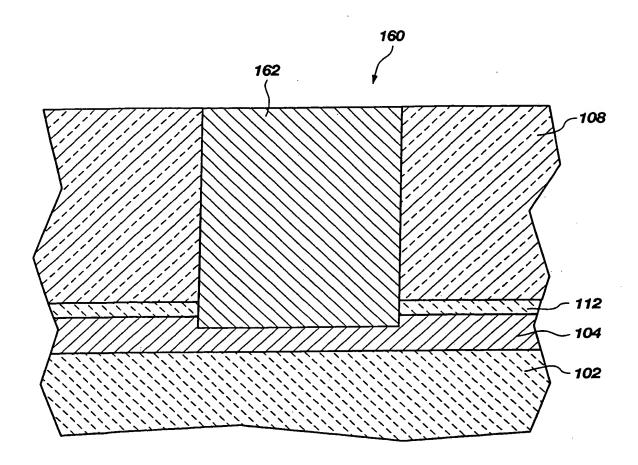


Fig. 10

TITLE: RESIDUE-FREE CONTACT OPENINGS AND METHODS FOR FABRICATING SAME

DE 23 2002 E

Inventor: Li Li Serial No.: 09/645,903 Docket No.: 2269-3361.2US

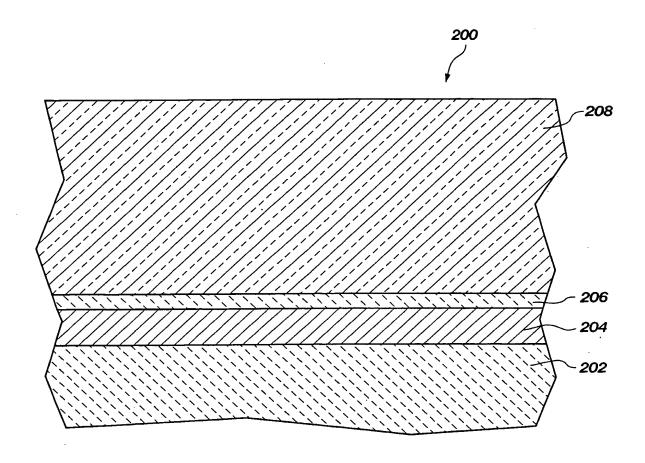


Fig. 11 (PRIOR ART)

TITLE: RESIDUE-FREE CONTACT OPENINGS AND METHODS FOR FABRICATING SAME



Inventor: Li Li Serial No.: 09/645,903 Docket No.: 2269-3361.2US

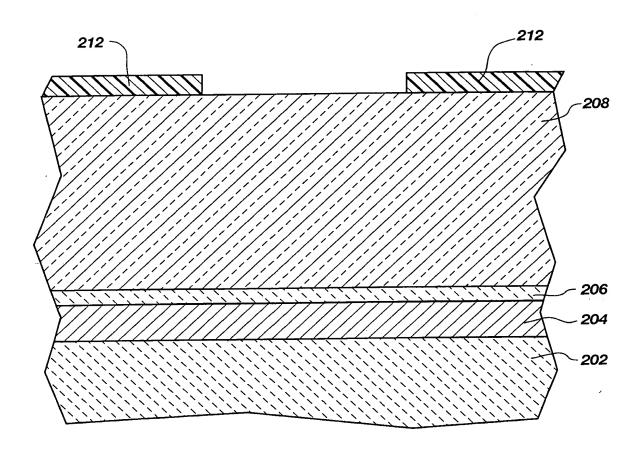


Fig. 12 (PRIOR ART)



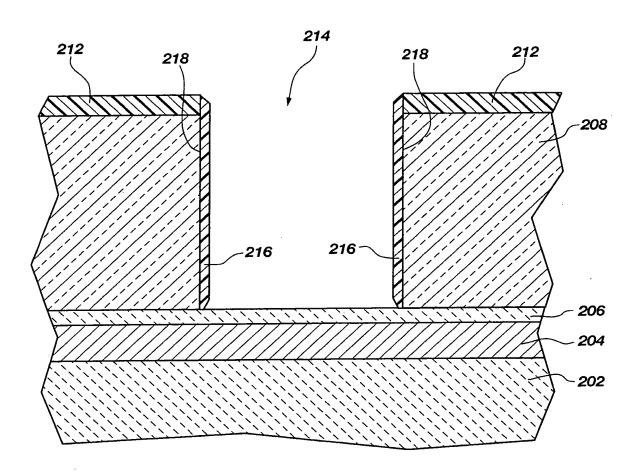


Fig. 13 (PRIOR ART)

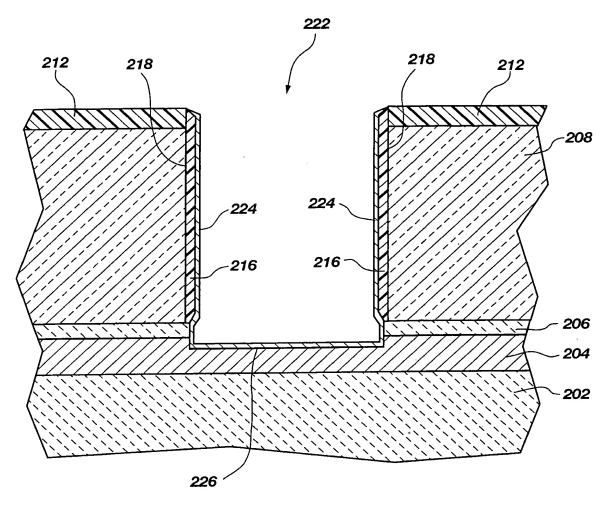


Fig. 14 (PRIOR ART)